

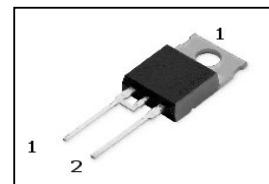
**2<sup>nd</sup> Generation thinQ!<sup>TM</sup> SiC Schottky Diode**
**Features**

- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery/ No forward recovery
- No temperature influence on the switching behavior
- High surge current capability
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>1)</sup> for target applications
- Breakdown voltage tested at 5mA<sup>2)</sup>

**Product Summary**

$V_{DC}$	600	V
$Q_c$	8	nC
$I_F$	4	A

PG-T0220-2-2


**thinQ! 2G Diode specially designed for fast switching applications like:**

- CCM PFC
- Motor Drives

Type	Package		Marking	Pin 1	Pin 2
IDT04S60C	PG-T0220-2-2		D04S60C	C	A

**Maximum ratings, at  $T_j=25$  °C, unless otherwise specified**

Parameter	Symbol	Conditions	Value	Unit
Continuous forward current	$I_F$	$T_c < 140$ °C	4	A
RMS forward current	$I_{F,RMS}$	$f=50$ Hz	5.6	
Surge non-repetitive forward current, sine halfwave	$I_{F,SM}$	$T_c = 25$ °C, $t_p = 10$ ms	32	
Repetitive peak forward current	$I_{F,RM}$	$T_j = 150$ °C, $T_c = 100$ °C, $D = 0.1$	18	
Non-repetitive peak forward current	$I_{F,max}$	$T_c = 25$ °C, $t_p = 10$ µs	132	
$i^2t$ value	$\int i^2 dt$	$T_c = 25$ °C, $t_p = 10$ ms	5.1	A <sup>2</sup> s
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Diode dv/dt ruggedness	$dv/dt$	$V_R = 0 \dots 480$ V	50	V/ns
Power dissipation	$P_{tot}$	$T_c = 25$ °C	42	W
Operating and storage temperature	$T_j, T_{stg}$		-55 ... 175	°C
Mounting torque		M3 and M3.5 screws	60	Mcm

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

**Thermal characteristics**

Thermal resistance, junction - case	$R_{thJC}$		-	-	3.6	K/W
Thermal resistance, junction - ambient	$R_{thJA}$	leaded	-	-	62	
Soldering temperature, wavesoldering only allowed at leads	$T_{sold}$	1.6mm (0.063 in.) from case for 10s	-	-	260	°C

**Electrical characteristics**, at  $T_j=25$  °C, unless otherwise specified

**Static characteristics**

DC blocking voltage	$V_{DC}$	$I_R=0.05$ mA	600	-	-	V
Diode forward voltage	$V_F$	$I_F=4$ A, $T_j=25$ °C	-	1.7	1.9	
		$I_F=4$ A, $T_j=150$ °C	-	2	2.4	
Reverse current	$I_R$	$V_R=600$ V, $T_j=25$ °C	-	0.5	50	μA
		$V_R=600$ V, $T_j=150$ °C	-	2	500	

**AC characteristics**

Total capacitive charge	$Q_c$	$V_R=400$ V, $I_F \leq I_{F,max}$ , $di_F/dt = 200$ A/μs,	-	8	-	nC
Switching time <sup>3)</sup>	$t_c$	$T_j=150$ °C	-	-	<10	ns
	$C$	$V_R=1$ V, $f=$ MHz	-	130	-	pF
		$V_R=300$ V, $f=1$ MHz	-	20	-	
		$V_R=600$ V, $f=1$ MHz	-	20	-	

<sup>1)</sup> J-STD20 and JESD22

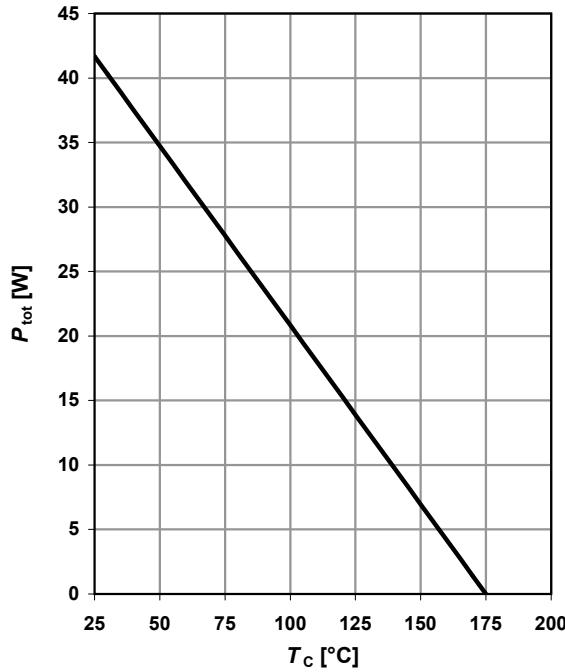
<sup>2)</sup> All devices tested under avalanche conditions, for a time period of 5ms, at 5mA.

<sup>3)</sup>  $t_c$  is the time constant for the capacitive displacement current waveform (independent from  $T_j$ ,  $I_{LOAD}$  and  $di/dt$ ), different from  $t_{rr}$ , which is dependent on  $T_j$ ,  $I_{LOAD}$ ,  $di/dt$ . No reverse recovery time constant  $t_{rr}$  due to absence of minority carrier injection.

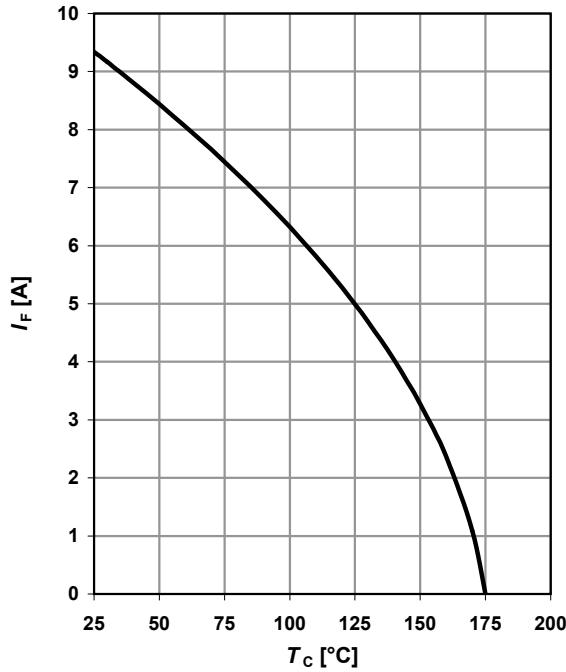
<sup>4)</sup> Only capacitive charge occurring, guaranteed by design.

**1 Power dissipation**

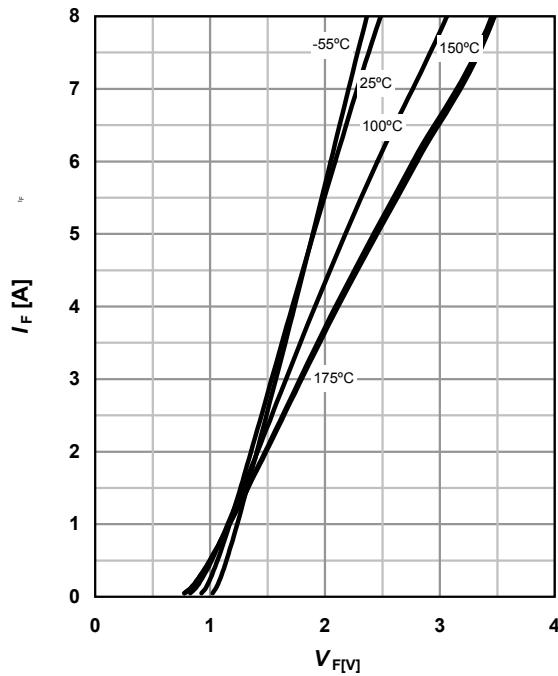
$$P_{\text{tot}} = f(T_c)$$

 parameter:  $R_{\text{thJC(max)}}$ 

**2 Diode forward current**

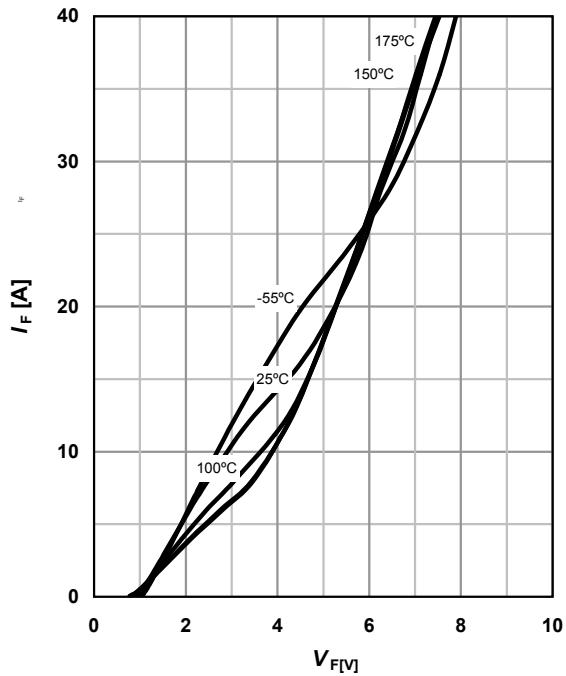
$$I_F = f(T_c); T_j \leq 175^\circ\text{C}$$

 parameter:  $R_{\text{thJC(max)}}, V_{F(\text{max})}$ 

**3 Typ. forward characteristic**

$$I_F = f(V_F); t_p = 400 \mu\text{s}$$

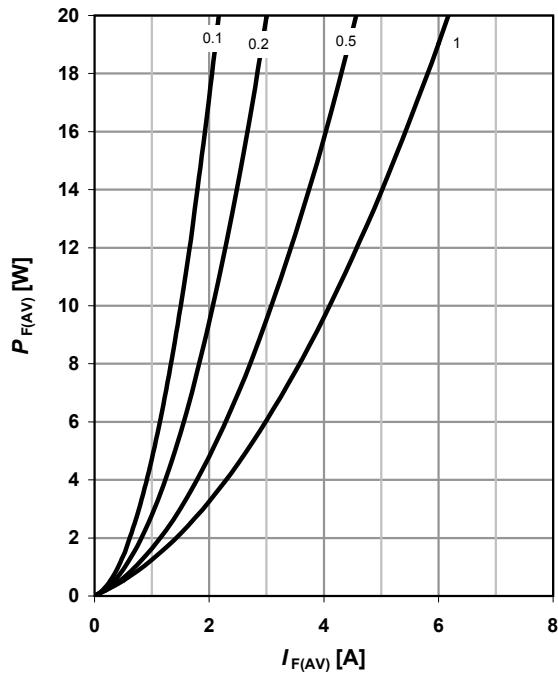
 parameter:  $T_j$ 

**4 Typ. forward characteristic in surge current mode**

$$I_F = f(V_F); t_p = 400 \mu\text{s}; \text{parameter: } T_j$$

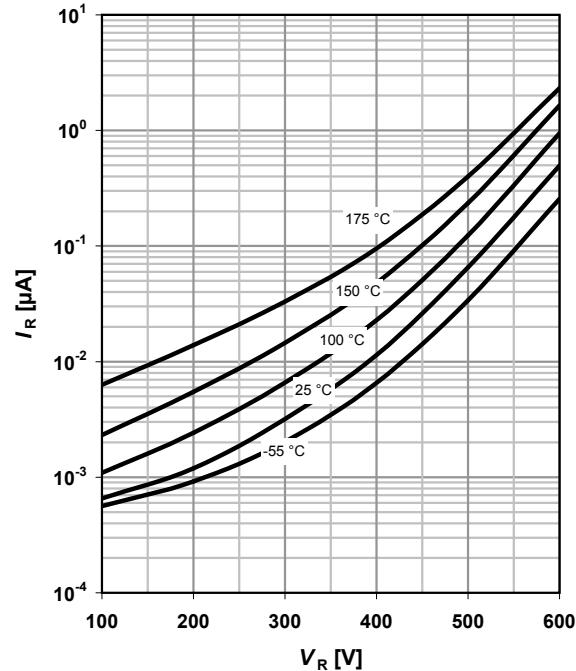


**5 Typ. forward power dissipation vs.**
**average forward current**

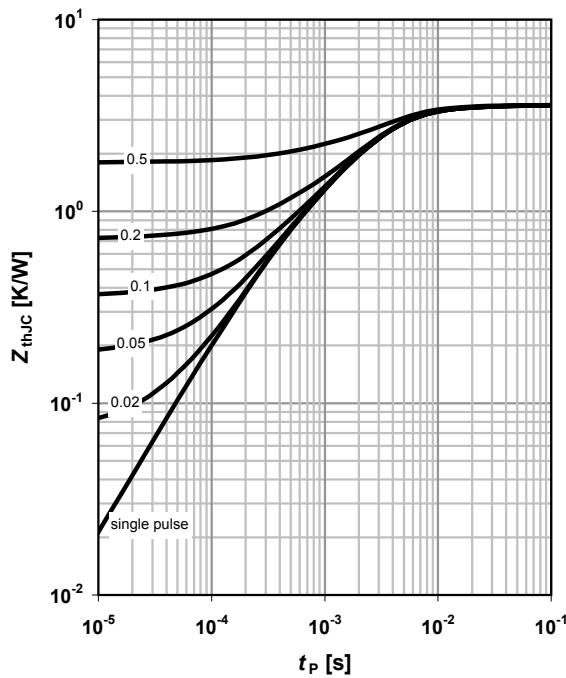
$$P_{F,AV} = f(I_F), T_C = 100 \text{ } ^\circ\text{C}, \text{ parameter: } D = t_p/T$$


**6 Typ. reverse current vs. reverse voltage**

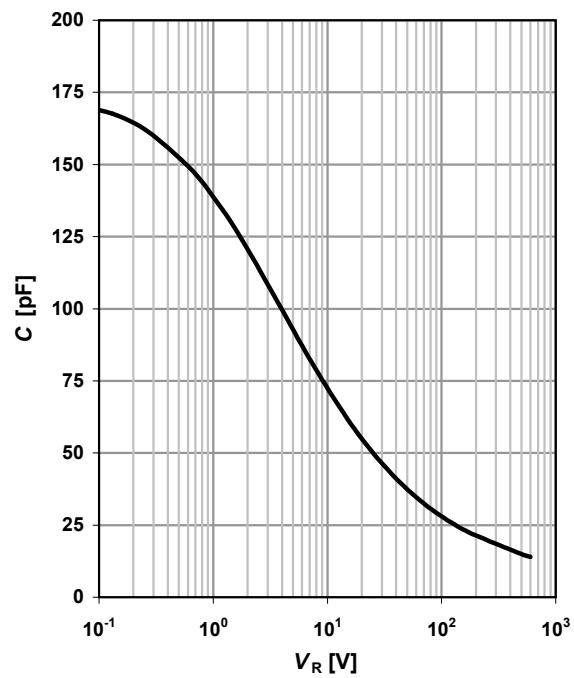
$$I_R = f(V_R)$$

**parameter:  $T_j$** 

**7 Transient thermal impedance**

$$Z_{thJC} = f(t_p)$$

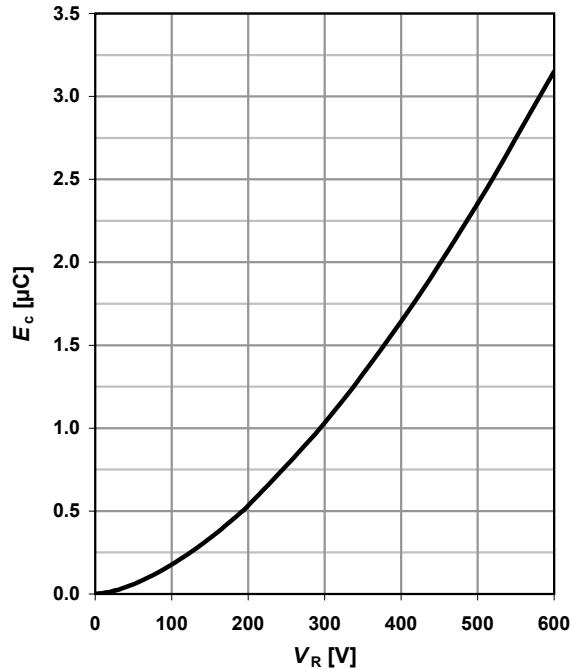
**parameter:  $D = t_p/T$** 

**8 Typ. capacitance vs. reverse voltage**

$$C = f(V_R); T_C = 25 \text{ } ^\circ\text{C}, f = 1 \text{ MHz}$$

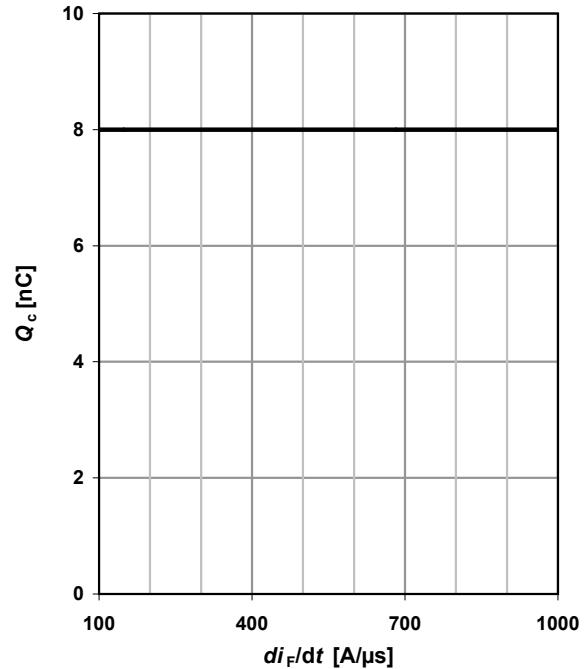


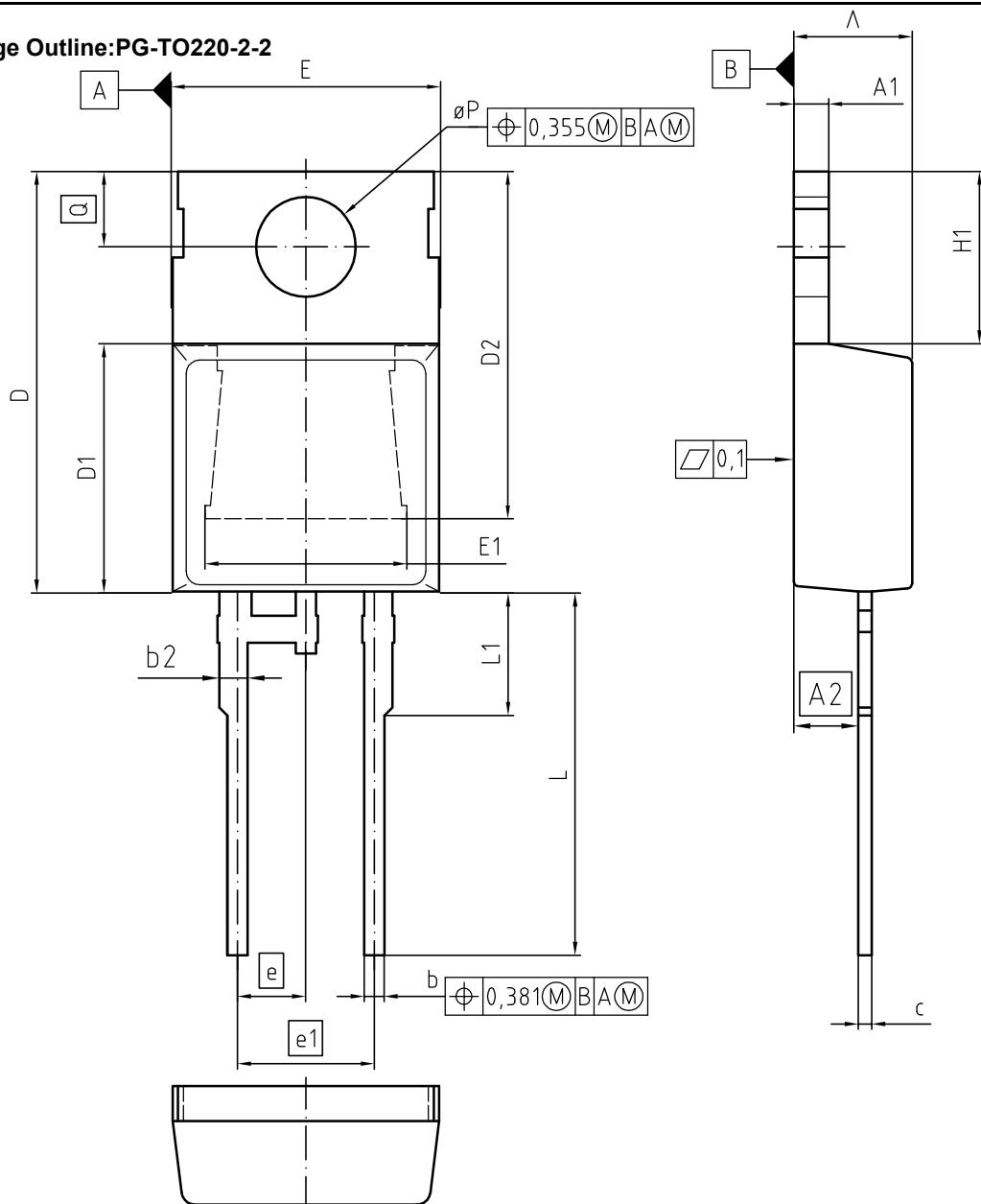
**9 Typ. C stored energy**

$$E_C = f(V_R)$$


**10 Typ. capacitance charge vs. current slope**

$$Q_C = f(di_F/dt)^4; T_J = 150 \text{ }^{\circ}\text{C}; I_F \leq I_{F,\max}$$



**Package Outline:PG-T0220-2-2**


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.191	4.699	0.165	0.185
A1	1.170	1.400	0.046	0.055
A2	2.215	2.718	0.087	0.107
b	0.635	0.889	0.025	0.035
b2	0.950	1.651	0.037	0.065
c	0.330	0.635	0.013	0.025
D	14.808	15.950	0.583	0.628
D1	8.509	9.450	0.335	0.372
D2	12.850	14.245	0.506	0.561
E	9.677	10.363	0.381	0.408
E1	6.500	8.788	0.256	0.346
e	2.540		0.100	
e1	5.080		0.200	
N	2		2	
H1	5.900	6.900	0.232	0.272
L	12.700	14.000	0.500	0.551
L1	3.048	4.800	0.120	0.189
ØP	3.550	3.886	0.140	0.153
Q	2.540	3.048	0.100	0.120

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SCALE	0 2.5 0 2.5 5mm
EUROPEAN PROJECTION	
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